

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)  
(Use several sheets if necessary)ATTY DOCKET NO.  
35.C14978APPLICATION NO.  
09/729,279APPLICANTS  
TAKESHI YAMAWAKI ET AL.FILING DATE  
December 5, 2000GROUP  
2852

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
SL	11-14923	1/22/99	Japan			Abstract
SL	9-96769	4/8/97	Japan			Abstract

## OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER

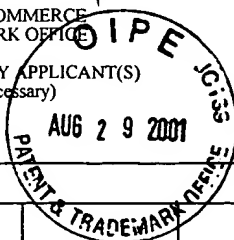
A. Lee

DATE CONSIDERED

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Sheet 1 of 1

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